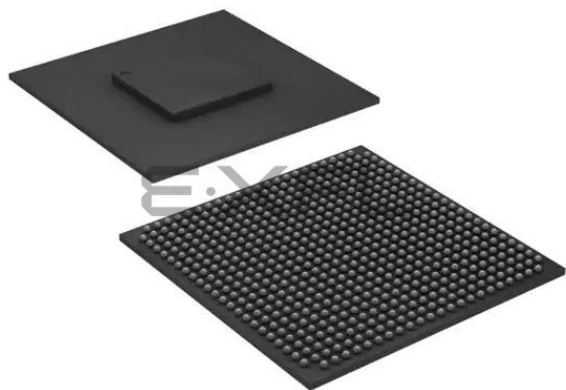




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Details

Product Status	Obsolete
Number of LABs/CLBs	1805
Number of Logic Elements/Cells	42959
Total RAM Bits	3517440
Number of I/O	252
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	572-BGA, FCBGA
Supplier Device Package	572-FBGA, FC (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2agx45df25c5n

I/O Pin Leakage Current

Table 1-7 lists the Arria II GX I/O pin leakage current specifications.

Table 1-7. I/O Pin Leakage Current for Arria II GX Devices

Symbol	Description	Conditions	Min	Typ	Max	Unit
I_I	Input pin	$V_I = 0\text{ V to }V_{CCIOMAX}$	-10	—	10	μA
I_{OZ}	Tri-stated I/O pin	$V_O = 0\text{ V to }V_{CCIOMAX}$	-10	—	10	μA

Table 1-8 lists the Arria II GZ I/O pin leakage current specifications.

Table 1-8. I/O Pin Leakage Current for Arria II GZ Devices

Symbol	Description	Conditions	Min	Typ	Max	Unit
I_I	Input pin	$V_I = 0\text{ V to }V_{CCIOMAX}$	-20	—	20	μA
I_{OZ}	Tri-stated I/O pin	$V_O = 0\text{ V to }V_{CCIOMAX}$	-20	—	20	μA

Bus Hold

Bus hold retains the last valid logic state after the source driving it either enters the high impedance state or is removed. Each I/O pin has an option to enable bus hold in user mode. Bus hold is always disabled in configuration mode.

Table 1-9 lists bus hold specifications for Arria II GX devices.

Table 1-9. Bus Hold Parameters for Arria II GX Devices (Note 1)

Parameter	Symbol	Cond.	V _{CCIO} (V)												Unit
			1.2		1.5		1.8		2.5		3.0		3.3		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold low, sustaining current	I _{SUSL}	V _{IN} > V _{IL} (max.)	8	—	12	—	30	—	50	—	70	—	70	—	μA
Bus-hold high, sustaining current	I _{SUSH}	V _{IN} < V _{IL} (min.)	−8	—	−12	—	−30	—	−50	—	−70	—	−70	—	μA
Bus-hold low, overdrive current	I _{ODL}	0 V < V _{IN} < V _{CCIO}	—	125	—	175	—	200	—	300	—	500	—	500	μA
Bus-hold high, overdrive current	I _{ODH}	0 V < V _{IN} < V _{CCIO}	—	−125	—	−175	—	−200	—	−300	—	−500	—	−500	μA
Bus-hold trip point	V _{TRIP}	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Note to Table 1-9:

(1) The bus-hold trip points are based on calculated input voltages from the JEDEC standard.

Table 1-10 lists the bus hold specifications for Arria II GZ devices.

Table 1-10. Bus Hold Parameters for Arria II GZ Devices

Parameter	Symbol	Cond.	V _{CCIO} (V)										Unit
			1.2		1.5		1.8		2.5		3.0		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold Low sustaining current	I _{SUSL}	V _{IN} > V _{IL} (max.)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	μA
Bus-hold High sustaining current	I _{SUSH}	V _{IN} < V _{IH} (min.)	-22.5	—	-25.0	—	-30.0	—	-50.0	—	-70.0	—	μA
Bus-hold Low overdrive current	I _{ODL}	0V < V _{IN} < V _{CCIO}	—	120	—	160	—	200	—	300	—	500	μA
Bus-hold High overdrive current	I _{ODH}	0V < V _{IN} < V _{CCIO}	—	-120	—	-160	—	-200	—	-300	—	-500	μA
Bus-hold trip point	V _{TRIP}	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

OCT Specifications

Table 1-11 lists the Arria II GX device and differential OCT with and without calibration accuracy.

Table 1-11. OCT With and Without Calibration Specification for Arria II GX Device I/Os (Note 1) (Part 1 of 2)

Symbol	Description	Conditions (V)	Calibration Accuracy		Unit
			Commercial	Industrial	
25- Ω R_S 3.0, 2.5	25- Ω series OCT without calibration	$V_{CCIO} = 3.0, 2.5$	± 30	± 40	%
50- Ω R_S 3.0, 2.5	50- Ω series OCT without calibration	$V_{CCIO} = 3.0, 2.5$	± 30	± 40	%
25- Ω R_S 1.8	25- Ω series OCT without calibration	$V_{CCIO} = 1.8$	± 40	± 50	%
50- Ω R_S 1.8	50- Ω series OCT without calibration	$V_{CCIO} = 1.8$	± 40	± 50	%
25- Ω R_S 1.5, 1.2	25- Ω series OCT without calibration	$V_{CCIO} = 1.5, 1.2$	± 50	± 50	%
50- Ω R_S 1.5, 1.2	50- Ω series OCT without calibration	$V_{CCIO} = 1.5, 1.2$	± 50	± 50	%
25- Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2	25- Ω series OCT with calibration	$V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2$	± 10	± 10	%

The calibration accuracy for calibrated series and parallel OCTs are applicable at the moment of calibration. When process, voltage, and temperature (PVT) conditions change after calibration, the tolerance may change.

Table 1-13 lists the Arria II GZ OCT without calibration resistance tolerance to PVT changes.

Table 1-13. OCT Without Calibration Resistance Tolerance Specifications for Arria II GZ Devices

Symbol	Description	Conditions (V)	Resistance Tolerance		Unit
			C3,I3	C4,I4	
25-Ω R _S 3.0 and 2.5	25-Ω internal series OCT without calibration	V _{CCIO} = 3.0, 2.5	± 40	± 40	%
25-Ω R _S 1.8 and 1.5	25-Ω internal series OCT without calibration	V _{CCIO} = 1.8, 1.5	± 40	± 40	%
25-Ω R _S 1.2	25-Ω internal series OCT without calibration	V _{CCIO} = 1.2	± 50	± 50	%
50-Ω R _S 3.0 and 2.5	50-Ω internal series OCT without calibration	V _{CCIO} = 3.0, 2.5	± 40	± 40	%
50-Ω R _S 1.8 and 1.5	50-Ω internal series OCT without calibration	V _{CCIO} = 1.8, 1.5	± 40	± 40	%
50-Ω R _S 1.2	50-Ω internal series OCT without calibration	V _{CCIO} = 1.2	± 50	± 50	%
100-Ω R _D 2.5	100-Ω internal differential OCT	V _{CCIO} = 2.5	± 25	± 25	%

OCT calibration is automatically performed at power up for OCT-enabled I/Os. When voltage and temperature conditions change after calibration, the resistance may change. Use Equation 1-1 and Table 1-14 to determine the OCT variation when voltage and temperature vary after power-up calibration for Arria II GX and GZ devices.

Equation 1-1. OCT Variation (Note 1)

$$R_{OCT} = R_{SCAL} \left(1 + \left\langle \frac{dR}{dT} \times \Delta T \right\rangle \pm \left\langle \frac{dR}{dV} \times \Delta V \right\rangle \right)$$

Notes to Equation 1-1:

- (1) R_{OCT} value calculated from Equation 1-1 shows the range of OCT resistance with the variation of temperature and V_{CCIO}.

Table 1–23. Single-Ended I/O Standards for Arria II GZ Devices (Part 2 of 2)

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
1.2 V	1.14	1.2	1.26	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	2	-2
3.0-V PCI	2.85	3	3.15	—	$0.3 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	3.6	$0.1 \times V_{CCIO}$	$0.9 \times V_{CCIO}$	1.5	-0.5
3.0-V PCI-X	2.85	3	3.15	—	$0.35 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	—	$0.1 \times V_{CCIO}$	$0.9 \times V_{CCIO}$	1.5	-0.5

Table 1–24 lists the single-ended SSTL and HSTL I/O reference voltage specifications for Arria II GX devices.

Table 1–24. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	$0.49 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.51 \times V_{CCIO}$	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-15 Class I, II	1.425	1.5	1.575	$0.47 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.53 \times V_{CCIO}$	$0.47 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.53 \times V_{CCIO}$
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	$0.48 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.52 \times V_{CCIO}$	—	$V_{CCIO}/2$	—

Table 1–25 lists the single-ended SSTL and HSTL I/O reference voltage specifications for Arria II GZ devices.

Table 1–25. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	$0.49 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.51 \times V_{CCIO}$	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-15 Class I, II	1.425	1.5	1.575	$0.47 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.53 \times V_{CCIO}$	$0.47 \times V_{CCIO}$	V_{REF}	$0.53 \times V_{CCIO}$
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	—	$V_{CCIO}/2$	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.68	0.75	0.9	—	$V_{CCIO}/2$	—
HSTL-12 Class I, II	1.14	1.2	1.26	$0.47 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.53 \times V_{CCIO}$	—	$V_{CCIO}/2$	—

Table 1–34. Transceiver Specifications for Arria II GX Devices (Note 1) (Part 3 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
fixedclk clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	—	125	—	—	125	—	MHz
reconfig_clk clock frequency	Dynamic reconfig. clock frequency	2.5/ 37.5 (4)	—	50	2.5/ 37.5 (4)	—	50	2.5/ 37.5 (4)	—	50	2.5/ 37.5 (4)	—	50	MHz
Delta time between reconfig_clks (5)	—	—	—	2	—	—	2	—	—	2	—	—	2	ms
Transceiver block minimum power-down pulse width	—	—	1	—	—	1	—	—	1	—	—	1	—	μs
Receiver														
Supported I/O Standards	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, 2.5-V PCML, LVPECL, and LVDS													
Data rate (13)	—	600	—	6375	600	—	3750	600	—	3750	600	—	3125	Mbps
Absolute V _{MAX} for a receiver pin (6)	—	—	—	1.5	—	—	1.5	—	—	1.5	—	—	1.5	V
Absolute V _{MIN} for a receiver pin	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	V
Maximum peak-to-peak differential input voltage V _{ID} (diff p-p)	V _{ICM} = 0.82 V setting	—	—	2.7	—	—	2.7	—	—	2.7	—	—	2.7	V
	V _{ICM} = 1.1 V setting (7)	—	—	1.6	—	—	1.6	—	—	1.6	—	—	1.6	V

Table 1–34. Transceiver Specifications for Arria II GX Devices (Note 1) (Part 4 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Minimum peak-to-peak differential input voltage V_{ID} (diff p-p)	—	100	—	—	100	—	—	100	—	—	100	—	—	mV
V_{ICM}	$V_{ICM} = 0.82$ V setting	—	820	—	—	820	—	—	820	—	—	820	—	mV
	$V_{ICM} = 1.1$ V setting (7)	—	1100	—	—	1100	—	—	1100	—	—	1100	—	mV
Differential on-chip termination resistors	100- Ω setting	—	100	—	—	100	—	—	100	—	—	100	—	Ω
Return loss differential mode	PCIe				50 MHz to 1.25 GHz: –10dB									
	XAU1				100 MHz to 2.5 GHz: –10dB									
Return loss common mode	PCIe				50 MHz to 1.25 GHz: –6dB									
	XAU1				100 MHz to 2.5 GHz: –6dB									
Programmable PPM detector (8)	—	$\pm 62.5, 100, 125, 200, 250, 300, 500, 1000$												ppm
Run length	—	—	80	—	—	80	—	—	80	—	—	80	—	UI
Programmable equalization	—	—	—	7	—	—	7	—	—	7	—	—	7	dB
Signal detect/loss threshold	PCIe Mode	65	—	175	65	—	175	65	—	175	65	—	175	mV
CDR LTR time (9)	—	—	—	75	—	—	75	—	—	75	—	—	75	μ s
CDR minimum T1b (10)	—	15	—	—	15	—	—	15	—	—	15	—	—	μ s

Table 1–34. Transceiver Specifications for Arria II GX Devices (Note 1) (Part 7 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Digital reset pulse width	—	Minimum is 2 parallel clock cycles												

Notes to Table 1–34:

- (1) For AC-coupled links, the on-chip biasing circuit is switched off before and during configuration. Ensure that input specifications are not violated during this period.
- (2) The rise/fall time is specified from 20% to 80%.
- (3) To calculate the REFCLK rms phase jitter requirement at reference clock frequencies other than 100 MHz, use the following formula:
REFCLK rms phase jitter at f (MHz) = REFCLK rms phase jitter at 100 MHz * 100/f.
- (4) The minimum `reconfig_clk` frequency is 2.5 MHz if the transceiver channel is configured in **Transmitter only** mode. The minimum `reconfig_clk` frequency is 37.5 MHz if the transceiver channel is configured in **Receiver only** or **Receiver and Transmitter** mode. For more information, refer to [AN 558: Implementing Dynamic Reconfiguration in Arria II Devices](#).
- (5) If your design uses more than one dynamic reconfiguration controller instances (`altgx_reconfig`) to control the transceiver channels (`altgx`) physically located on the same side of the device, and if you use different `reconfig_clk` sources for these `altgx_reconfig` instances, the delta time between any two of these `reconfig_clk` sources becoming stable must not exceed the maximum specification listed.
- (6) The device cannot tolerate prolonged operation at this absolute maximum.
- (7) You must use the 1.1-V RX V_{ICM} setting if the input serial data standard is LVDS and the link is DC-coupled.
- (8) The rate matcher supports only up to ± 300 parts per million (ppm).
- (9) Time taken to `rx_pll_locked` goes high from `rx_analogreset` de-assertion. Refer to [Figure 1–1](#).
- (10) The time in which the CDR must be kept in lock-to-reference mode after `rx_pll_locked` goes high and before `rx_locktodata` is asserted in manual mode. Refer to [Figure 1–1](#).
- (11) The time taken to recover valid data after the `rx_locktodata` signal is asserted in manual mode. Refer to [Figure 1–1](#).
- (12) The time taken to recover valid data after the `rx_freqlocked` signal goes high in automatic mode. Refer to [Figure 1–2](#).
- (13) To support data rates lower than the minimum specification through oversampling, use the CDR in LTR mode only.

Figure 1-1 shows the lock time parameters in manual mode.

 LTD = lock-to-data. LTR = lock-to-reference.

Figure 1-1. Lock Time Parameters for Manual Mode

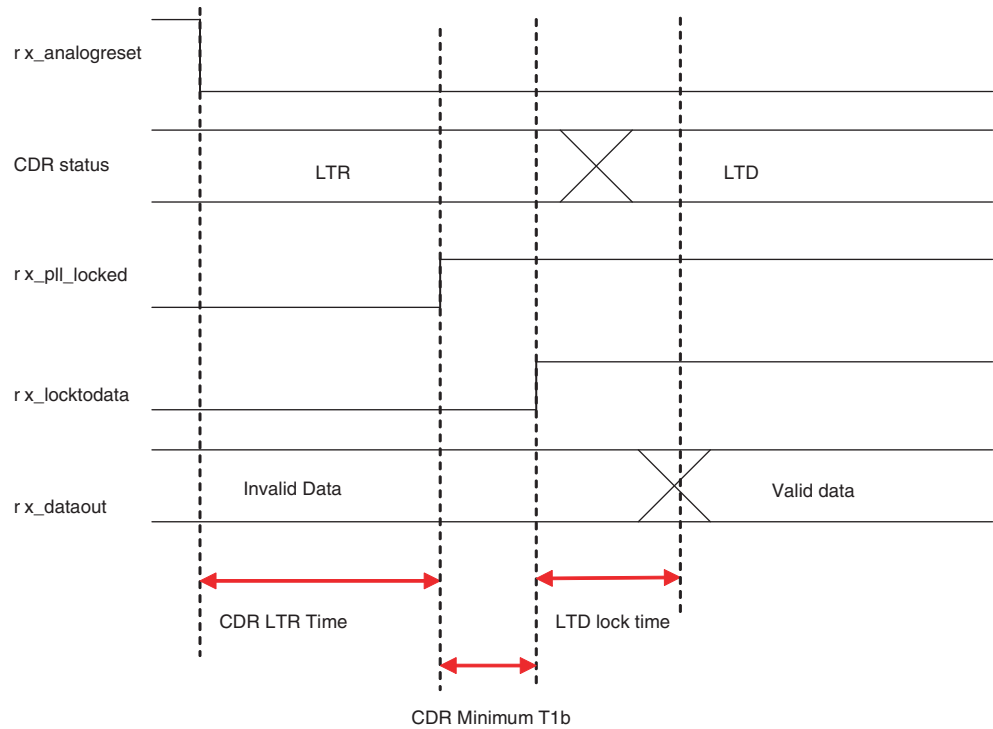


Figure 1-2 shows the lock time parameters in automatic mode.

Figure 1-2. Lock Time Parameters for Automatic Mode

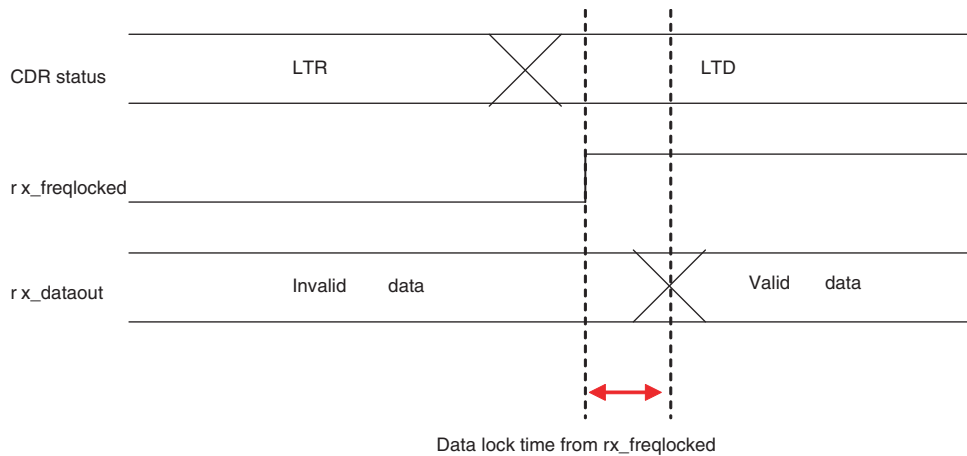


Figure 1-3 shows the differential receiver input waveform.

Figure 1-3. Receiver Input Waveform

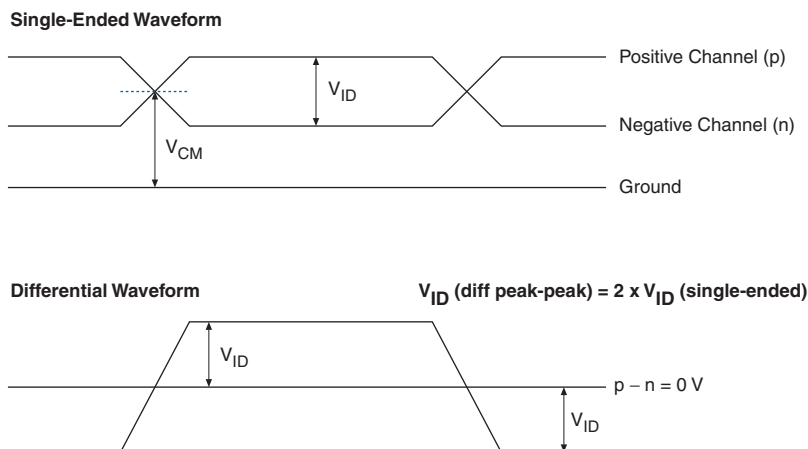


Figure 1-4 shows the transmitter output waveform.

Figure 1-4. Transmitter Output Waveform

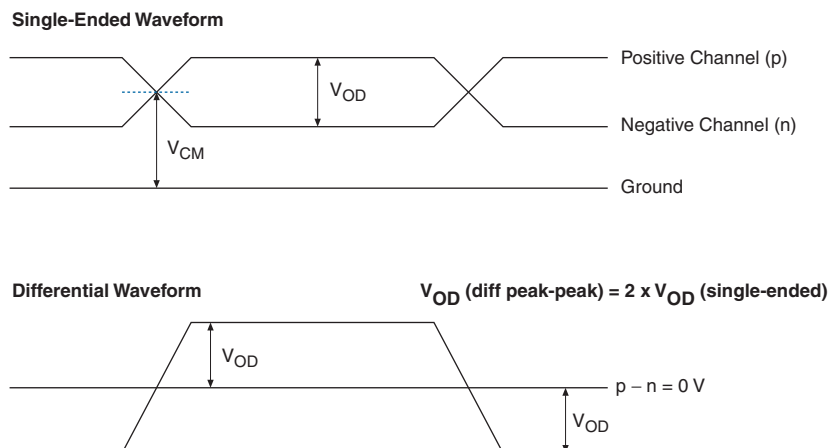


Table 1-36 lists the typical V_{OD} for TX term that equals $85\ \Omega$ for Arria II GZ devices.

Table 1-36. Typical V_{OD} Setting, TX Term = $85\ \Omega$ for Arria II GZ Devices

Symbol	V_{OD} Setting (mV)							
	0	1	2	3	4	5	6	7
V_{OD} differential peak-to-peak Typical (mV)	$170 \pm 20\%$	$340 \pm 20\%$	$510 \pm 20\%$	$595 \pm 20\%$	$680 \pm 20\%$	$765 \pm 20\%$	$850 \pm 20\%$	$1020 \pm 20\%$

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices (Note 1) (Part 9 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
OBSAI Receiver Jitter Tolerance (12)														
Deterministic jitter tolerance at 768 Mbps, 1536 Mbps, and 3072 Mbps	Pattern = CJPAT	> 0.37			> 0.37			> 0.37			> 0.37			UI
Combined deterministic and random jitter tolerance at 768 Mbps, 1536 Mbps, and 3072 Mbps	Pattern = CJPAT	> 0.55			> 0.55			> 0.55			> 0.55			UI
Sinusoidal jitter tolerance at 768 Mbps	Jitter frequency = 5.4 KHz Pattern = CJPAT	> 8.5			> 8.5			> 8.5			> 8.5			UI
	Jitter frequency = 460.8 KHz to 20 MHz Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI
Sinusoidal jitter tolerance at 1536 Mbps	Jitter frequency = 10.9 KHz Pattern = CJPAT	> 8.5			> 8.5			> 8.5			> 8.5			UI
	Jitter frequency = 921.6 KHz to 20 MHz Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices (Note 1), (2) (Part 2 of 7)

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Jitter tolerance at 2488.32 Mbps	Jitter frequency = 0.06 KHz Pattern = PRBS15	> 15			> 15			UI
	Jitter frequency = 100 KHZ Pattern = PRBS15	> 1.5			> 1.5			UI
	Jitter frequency = 1 MHz Pattern = PRBS15	> 0.15			> 0.15			UI
	Jitter frequency = 10 MHz Pattern = PRBS15	> 0.15			> 0.15			UI
Fibre Channel Transmit Jitter Generation (4), (5)								
Total jitter FC-1	Pattern = CRPAT	—	—	0.23	—	—	0.23	UI
Deterministic jitter FC-1	Pattern = CRPAT	—	—	0.11	—	—	0.11	UI
Total jitter FC-2	Pattern = CRPAT	—	—	0.33	—	—	0.33	UI
Deterministic jitter FC-2	Pattern = CRPAT	—	—	0.2	—	—	0.2	UI
Total jitter FC-4	Pattern = CRPAT	—	—	0.52	—	—	0.52	UI
Deterministic jitter FC-4	Pattern = CRPAT	—	—	0.33	—	—	0.33	UI
Fibre Channel Receiver Jitter Tolerance (4), (6)								
Deterministic jitter FC-1	Pattern = CJTPAT	> 0.37			> 0.37			UI
Random jitter FC-1	Pattern = CJTPAT	> 0.31			> 0.31			UI
Sinusoidal jitter FC-1	Fc/25000	> 1.5			> 1.5			UI
	Fc/1667	> 0.1			> 0.1			UI
Deterministic jitter FC-2	Pattern = CJTPAT	> 0.33			> 0.33			UI
Random jitter FC-2	Pattern = CJTPAT	> 0.29			> 0.29			UI
Sinusoidal jitter FC-2	Fc/25000	> 1.5			> 1.5			UI
	Fc/1667	> 0.1			> 0.1			UI
Deterministic jitter FC-4	Pattern = CJTPAT	> 0.33			> 0.33			UI
Random jitter FC-4	Pattern = CJTPAT	> 0.29			> 0.29			UI
Sinusoidal jitter FC-4	Fc/25000	> 1.5			> 1.5			UI
	Fc/1667	> 0.1			> 0.1			UI
XAUI Transmit Jitter Generation (7)								
Total jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.3	—	—	0.3	UI
Deterministic jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.17	—	—	0.17	UI
XAUI Receiver Jitter Tolerance (7)								
Total jitter	—	> 0.65			> 0.65			UI
Deterministic jitter	—	> 0.37			> 0.37			UI

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices (Note 1), (2) (Part 3 of 7)

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Peak-to-peak jitter	Jitter frequency = 22.1 KHz	> 8.5			> 8.5			UI
Peak-to-peak jitter	Jitter frequency = 1.875 MHz	> 0.1			> 0.1			UI
Peak-to-peak jitter	Jitter frequency = 20 MHz	> 0.1			> 0.1			UI
PCIe Transmit Jitter Generation (8)								
Total jitter at 2.5 Gbps (Gen1)— x1, x4, and x8	Compliance pattern	—	—	0.25	—	—	0.25	UI
Total jitter at 5 Gbps (Gen2)— x1, x4, and x8	Compliance pattern	—	—	0.25	—	—	—	UI
PCIe Receiver Jitter Tolerance (8)								
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	> 0.6			> 0.6			UI
Total jitter at 5 Gbps (Gen2)	Compliance pattern	Not supported			Not supported			UI
PCIe (Gen 1) Electrical Idle Detect Threshold								
V _{RX-IDLE-DETDIFFp-p} (9)	Compliance pattern	65	—	175	65	—	175	UI
SRIO Transmit Jitter Generation (10)								
Deterministic jitter (peak-to-peak)	Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	—	—	0.17	—	—	0.17	UI
Total jitter (peak-to-peak)	Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
SRIO Receiver Jitter Tolerance (10)								
Deterministic jitter tolerance (peak-to-peak)	Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.37			> 0.37			UI
Combined deterministic and random jitter tolerance (peak-to- peak)	Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.55			> 0.55			UI
Sinusoidal jitter tolerance (peak- to-peak)	Jitter frequency = 22.1 KHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 8.5			> 8.5			UI
	Jitter frequency = 1.875 MHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.1			> 0.1			UI
	Jitter frequency = 20 MHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.1			> 0.1			UI
GIGE Transmit Jitter Generation (11)								
Deterministic jitter (peak-to-peak)	Pattern = CRPAT	—	—	0.14	—	—	0.14	UI
Total jitter (peak-to-peak)	Pattern = CRPAT	—	—	0.279	—	—	0.279	UI

Core Performance Specifications for the Arria II Device Family

This section describes the clock tree, phase-locked loop (PLL), digital signal processing (DSP), embedded memory, configuration, and JTAG specifications for Arria II GX and GZ devices.

Clock Tree Specifications

Table 1-42 lists the clock tree specifications for Arria II GX devices.

Table 1-42. Clock Tree Performance for Arria II GX Devices

Clock Network	Performance			Unit
	I3, C4	C5,I5	C6	
GCLK and RCLK	500	500	400	MHz
PCLK	420	350	280	MHz

Table 1-43 lists the clock tree specifications for Arria II GZ devices.

Table 1-43. Clock Tree Performance for Arria II GZ Devices

Clock Network	Performance		Unit
	-C3 and -I3	-C4 and -I4	
GCLK and RCLK	700	500	MHz
PCLK	500	450	MHz

PLL Specifications

Table 1-44 lists the PLL specifications for Arria II GX devices.

Table 1-44. PLL Specifications for Arria II GX Devices (Part 1 of 3)

Symbol	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (from clock input pins residing in right/top/bottom banks) (-4 Speed Grade)	5	—	670 (1)	MHz
	Input clock frequency (from clock input pins residing in right/top/bottom banks) (-5 Speed Grade)	5	—	622 (1)	MHz
	Input clock frequency (from clock input pins residing in right/top/bottom banks) (-6 Speed Grade)	5	—	500 (1)	MHz
f_{INPFD}	Input frequency to the PFD	5	—	325	MHz
f_{VCO}	PLL VCO operating Range (2)	600	—	1,400	MHz
f_{INDUTY}	Input clock duty cycle	40	—	60	%
$f_{EINDUTY}$	External feedback clock input duty cycle	40	—	60	%
t_{INCCJ} (3), (4)	Input clock cycle-to-cycle jitter (Frequency ≥ 100 MHz)	—	—	0.15	UI (p-p)
	Input clock cycle-to-cycle jitter (Frequency ≤ 100 MHz)	—	—	± 750	ps (p-p)

Table 1-44. PLL Specifications for Arria II GX Devices (Part 3 of 3)

Symbol	Description	Min	Typ	Max	Unit
$t_{CASC_OUTJITTER_PERIOD_DEDCLK}$ (6), (7)	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} \geq 100$ MHz)	—	—	425	ps (p-p)
	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} \leq 100$ MHz)	—	—	42.5	mUI (p-p)

Notes to Table 1-44:

- (1) f_{IN} is limited by the I/O f_{MAX} .
- (2) The VCO frequency reported by the Quartus II software in the PLL summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VCO} specification.
- (3) A high-input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean-clock source, which is less than 200 ps.
- (4) F_{REF} is f_{IN}/N when $N = 1$.
- (5) This specification is limited by the lower of the two: I/O f_{MAX} or f_{OUT} of the PLL.
- (6) Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Table 1-62 on page 1-70.
- (7) The cascaded PLL specification is only applicable with the following condition:
 - a. Upstream PLL: $0.59 \text{ MHz} \leq \text{Upstream PLL BW} < 1 \text{ MHz}$
 - b. Downstream PLL: $\text{Downstream PLL BW} > 2 \text{ MHz}$

Table 1-45 lists the PLL specifications for Arria II GZ devices when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (-40° to 100°C).

Table 1-45. PLL Specifications for Arria II GZ Devices (Part 1 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (-3 speed grade)	5	—	717 (1)	MHz
	Input clock frequency (-4 speed grade)	5	—	717 (1)	MHz
f_{INPFD}	Input frequency to the PFD	5	—	325	MHz
f_{VCO}	PLL VCO operating range (-3 speed grade)	600	—	1,300	MHz
	PLL VCO operating range (-4 speed grade)	600	—	1,300	MHz
$t_{EINDUTY}$	Input clock or external feedback clock input duty cycle	40	—	60	%
f_{OUT}	Output frequency for internal global or regional clock (-3 speed grade)	—	—	700 (2)	MHz
	Output frequency for internal global or regional clock (-4 speed grade)	—	—	500 (2)	MHz
f_{OUT_EXT}	Output frequency for external clock output (-3 speed grade)	—	—	717 (2)	MHz
	Output frequency for external clock output (-4 speed grade)	—	—	717 (2)	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45	50	55	%
t_{FCOMP}	External feedback clock compensation time	—	—	10	ns
$t_{CONFIGPLL}$	Time required to reconfigure scan chain	—	3.5	—	scanclk cycles
$t_{CONFIGPHASE}$	Time required to reconfigure phase shift	—	1	—	scanclk cycles
$f_{SCANCLK}$	scanclk frequency	—	—	100	MHz
t_{LOCK}	Time required to lock from end-of-device configuration or de-assertion of areset	—	—	1	ms

Periphery Performance

This section describes periphery performance, including high-speed I/O, external memory interface, and IOE programmable delay.

I/O performance supports several system interfaces, for example the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/O using SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speed with typical DDR2 SDRAM memory interface setup. I/O using general purpose I/O (GPIO) standards such as 3.0, 2.5, 1.8, or 1.5 LVTTTL/LVCMOS are capable of typical 200 MHz interfacing frequency with 10pF load.



Actual achievable frequency depends on design- and system-specific factors. You should perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 1-53 lists the high-speed I/O timing for Arria II GX devices.

Table 1-53. High-Speed I/O Specifications for Arria II GX Devices (Part 1 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Clock										
f _{HCLK_IN} (input clock frequency)–Row I/O	Clock boost factor, W = 1 to 40 (1)	5	670	5	670	5	622	5	500	MHz
f _{HCLK_IN} (input clock frequency)–Column I/O	Clock boost factor, W = 1 to 40 (1)	5	500	5	500	5	472.5	5	472.5	MHz
f _{HCLK_OUT} (output clock frequency)–Row I/O	—	5	670	5	670	5	622	5	500	MHz
f _{HCLK_OUT} (output clock frequency)–Column I/O	—	5	500	5	500	5	472.5	5	472.5	MHz

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 2 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Transmitter										
f _{HSDR_TX} (true LVDS output data rate)	SERDES factor, J = 3 to 10 (using dedicated SERDES)	150	1250 (2)	150	1250 (2)	150	1050 (2)	150	840	Mbps
	SERDES factor, J = 4 to 10 (using logic elements as SERDES)	(3)	945	(3)	945	(3)	840	(3)	740	Mbps
	SERDES factor, J = 2 (using DDR registers) and J = 1 (using SDR register)	(3)	(3)	(3)	(3)	(3)	(3)	(3)	(3)	Mbps
f _{HSDR_TX_E3R} (emulated LVDS_E_3R output data rate) (7)	SERDES factor, J = 4 to 10	(3)	945	(3)	945	(3)	840	(3)	740	Mbps

Table 1-55. DPA Lock Time Specifications for Arria II Devices (Note 1), (2), (3)

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions (4)	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Notes to Table 1-55:

- (1) The DPA lock time is for one channel.
- (2) One data transition is defined as a 0-to-1 or 1-to-0 transition.
- (3) The DPA lock time stated in the table applies to both commercial and industrial grade.
- (4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 1-5 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for Arria II GZ devices at a data rate less than 1.25 Gbps and all the Arria II GX devices.

Figure 1-5. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for All Arria II GX Devices and for Arria II GZ Devices at a Data Rate less than 1.25 Gbps

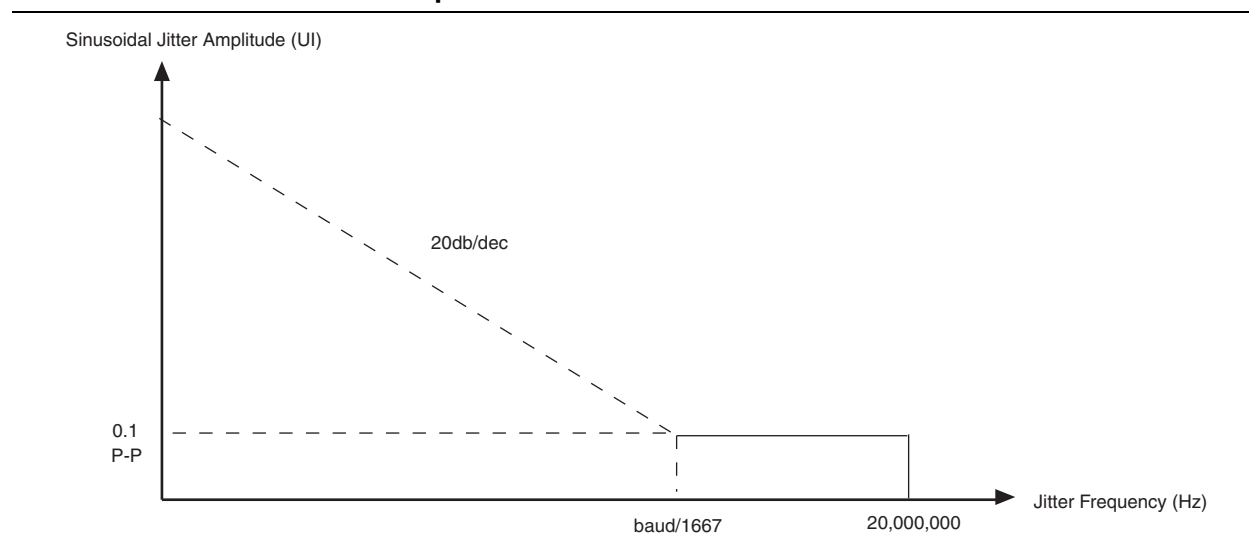


Table 1-57. External Memory Interface Specifications for Arria II GX Devices (Part 2 of 2)

Frequency Mode	Frequency Range (MHz)			Resolution (°)	DQS Delay Buffer Mode (1)	Number of Delay Chains
	C4	I3, C5, I5	C6			
5	270-410	270-380	270-320	36	High	10
6	320-450	320-410	320-370	45	High	8

Note to Table 1-57:

(1) Low indicates a 6-bit DQS delay setting; high indicates a 5-bit DQS delay setting.

Table 1-58 lists the DLL frequency range specifications for Arria II GZ devices.

Table 1-58. DLL Frequency Range Specifications for Arria II GZ Devices

Frequency Mode	Frequency Range (MHz)		Available Phase Shift	DQS Delay Buffer Mode (1)	Number of Delay Chains
	-3	-4			
0	90-130	90-120	22.5°, 45°, 67.5°, 90°	Low	16
1	120-170	120-160	30°, 60°, 90°, 120°	Low	12
2	150-210	150-200	36°, 72°, 108°, 144°	Low	10
3	180-260	180-240	45°, 90°, 135°, 180°	Low	8
4	240-320	240-290	30°, 60°, 90°, 120°	High	12
5	290-380	290-360	36°, 72°, 108°, 144°	High	10
6	360-450	360-450	45°, 90°, 135°, 180°	High	8
7	470-630	470-590	60°, 120°, 180°, 240°	High	6

Note to Table 1-58:

(1) Low indicates a 6-bit DQS delay setting; high indicates a 5-bit DQS delay setting.

Table 1-59 lists the DQS phase offset delay per stage for Arria II GX devices.

Table 1-59. DQS Phase Offset Delay Per Setting for Arria II GX Devices (Note 1), (2), (3)

Speed Grade	Min	Max	Unit
C4	7.0	13.0	ps
I3, C5, I5	7.0	15.0	ps
C6	8.5	18.0	ps

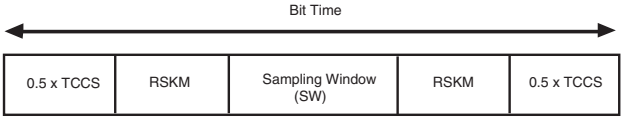
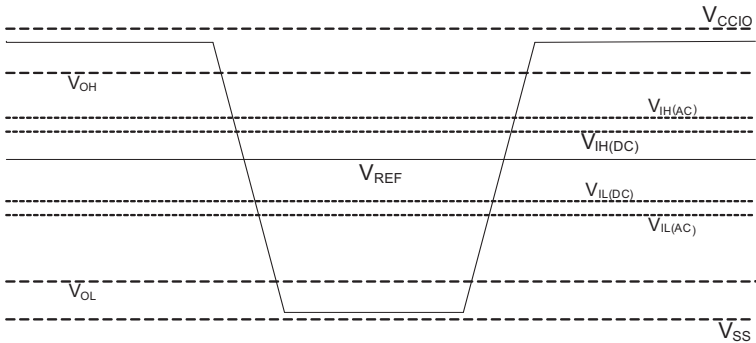
Notes to Table 1-59:

- (1) The valid settings for phase offset are -64 to +63 for frequency modes 0 to 3 and -32 to +31 for frequency modes 4 to 5.
- (2) The typical value equals the average of the minimum and maximum values.
- (3) The delay settings are linear.

Table 1-68. Glossary (Part 2 of 4)

Letter	Subject	Definitions
G, H, I, J	J	High-speed I/O block: Deserialization factor (width of parallel data bus).
	JTAG Timing Specifications	JTAG Timing Specifications:
K, L, M, N, O, P	PLL Specifications	PLL Specification parameters: Diagram of PLL Specifications (1) Notes: (1) CoreClock can only be fed by dedicated clock input pins or PLL outputs. (2) This is the VCO post-scale counter K.
Q, R	R _L	Receiver differential input discrete resistor (external to the Arria II device).

Table 1-68. Glossary (Part 3 of 4)

Letter	Subject	Definitions
S	SW (sampling window)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window: <i>Timing Diagram</i> 
	Single-ended Voltage Referenced I/O Standard	The JEDEC standard for SSTL and HSTL I/O standards define both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the AC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: <i>Single-Ended Voltage Referenced I/O Standard</i> 
T	t_c	High-speed receiver and transmitter input and output clock period.
	TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under S in this table).
	t_{DUTY}	High-speed I/O block: Duty cycle on the high-speed transmitter output clock. Timing Unit Interval (TUI) The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = $1/(\text{Receiver Input Clock Frequency Multiplication Factor}) = t_c/w$)
	t_{FALL}	Signal high-to-low transition time (80-20%)
	t_{INCCJ}	Cycle-to-cycle jitter tolerance on the PLL clock input.
	t_{OUTPJ_IO}	Period jitter on the general purpose I/O driven by a PLL.
	t_{OUTPJ_DC}	Period jitter on the dedicated clock output driven by a PLL.
	t_{RISE}	Signal low-to-high transition time (20-80%).